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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, FlexIO, I ² C, LINbus, SPI, UART/USART
Peripherals	POR, PWM, WDT
Number of I/O	58
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b SAR; D/A1x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/fs32k144hrt0vlht

Description Input Multiplexing sheet(s) attached with Reference Manual.

	Parameter	S32K11x		S32K14x			
		K116	K118	K142	K144	K146	K148
System	Core	Arm® Cortex™-M0+		Arm® Cortex™-M4F			
	Frequency	48 MHz		80 MHz (RUN mode) or 112 MHz (HSRUN mode) ¹			
	IEEE-754 FPU	○		●			
	Cryptographic Services Engine (CSEc) ¹	●		●			
	CRC module	1x		1x			
	ISO 26262	capable up to ASIL-B		capable up to ASIL-B			
	Peripheral speed	up to 48 MHz		up to 112 MHz (HSRUN)			
	Crossbar	●		●			
	DMA	●		●			
	External Watchdog Monitor (EWM)	○		●			
	Memory Protection Unit (MPU)	●		●			
	FIRC CMU	●		○			
	Watchdog	1x		1x			
	Low power modes	●		●			
	HSRUN mode ¹	○		●			
	Number of I/Os	up to 43	up to 58	up to 89	up to 128	up to 156	
	Single supply voltage	2.7 - 5.5 V		2.7 - 5.5 V			
	Ambient Operation Temperature (T _A)	-40°C to +105°C / +125°C		-40°C to +105°C / +125°C			
Memory	Flash	128 KB	256 KB	256 KB	512 KB	1 MB	2 MB ²
	Error Correcting Code (ECC)	●		●			
	System RAM (including FlexRAM and MTB)	17 KB	25 KB	32 KB	64 KB	128 KB	256 KB
	FlexRAM (also available as system RAM)	2 KB		4 KB			
	Cache	○		4 KB			
	EEPROM emulated by FlexRAM ¹	2 KB (up to 32 KB D-Flash)		4 KB (up to 64 KB D-Flash)			See footnote 3
	External memory interface	○		○			QuadSPI incl. HyperBus™
Timer	Low Power Interrupt Timer (LPIT)	1x		1x			
	FlexTimer (16-bit counter) 8 channels	2x (16)		4x (32)		6x (48)	8x (64)
	Low Power Timer (LPTMR)	1x		1x			
	Real Time Counter (RTC)	1x		1x			
	Programmable Delay Block (PDB)	1x		2x			
Analog	Trigger mux (TRGMUX)	1x (43)	1x (45)	1x (64)		1x (73)	1x (81)
	12-bit SAR ADC (1 Msps each)	1x (13)	1x (16)	2x (16)		2x (24)	2x (32)
	Comparator with 8-bit DAC	1x		1x			
Communication	10/100 Mbps IEEE-1588 Ethernet MAC	○		○			1x
	Serial Audio Interface (AC97, TDM, I2S)	○		○			2x
	Low Power UART/LIN (LPUART) (Supports LIN protocol versions 1.3, 2.0, 2.1, 2.2A, and SAE J2602)	2x		2x	3x		
	Low Power SPI (LPSPPI)	1x	2x	2x	3x		
	Low Power I2C (LPI2C)	1x		1x			2x
	FlexCAN (CAN-FD ISO/CD 11898-1)	1x (1x with FD)		2x (1x with FD)	3x (1x with FD)	3x (2x with FD)	3x (3x with FD)
	FlexIO (8 pins configurable as UART, SPI, I2C, I2S)	1x		1x			
IDEs	Debug & trace	SWD, MTB (1 KB), JTAG ⁴		SWD, JTAG (ITM, SWV, SWO)			SWD, JTAG (ITM, SWV, SWO), ETM
	Ecosystem (IDE, compiler, debugger)	NXP S32 Design Studio (GCC) + SDK, IAR, GHS, Arm®, Lauterbach, iSystems		NXP S32 Design Studio (GCC) + SDK, IAR, GHS, Arm®, Lauterbach, iSystems			
Other	Packages ⁵	32-pin QFN 48-pin LQFP	48-pin LQFP 64-pin LQFP	64-pin LQFP 100-pin LQFP	64-pin LQFP 100-pin LQFP 100-pin MAPBGA	64-pin LQFP 100-pin MAPBGA 100-pin LQFP 144-pin LQFP	100-pin MAPBGA 144-pin LQFP 176-pin LQFP

LEGEND:

○ Not implemented

● Available on the device

1 No write or erase access to Flash module, including Security (CSEc) and EEPROM commands, are allowed when device is running at HSRUN mode (112MHz) or VLPR mode.

2 Available when EEPROM, CSEc and Data Flash are not used. Else only up to 1,984 KB is available for Program Flash.

3 4 KB (up to 512 KB D-Flash as a part of 2 MB Flash). Up to 64 KB of flash is used as EEPROM backup and the remaining 448 KB of the last 512 KB block can be used as Data flash or Program flash. See chapter FTFC for details.

4 Only for Boundary Scan Register

5 See Dimensions section for package drawings

Figure 3. S32K1xx product series comparison

Table 7. Power consumption (Typicals unless stated otherwise) ¹

Chip/Device	Ambient Temperature (°C)		VLPS (μA) ²		VLPR (mA)			STOP1 (mA)	STOP2 (mA)	RUN@48 MHz (mA)		RUN@64 MHz (mA)		RUN@80 MHz (mA)		HSRUN@112 MHz (mA) ³		IDD/MHz (μA/MHz) ⁴
			Peripherals disabled ⁵	Peripherals enabled	Peripherals disabled ⁶	Peripherals enabled use case 1 ⁶	Peripherals enabled use case 2 ⁷			Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	Peripherals disabled	Peripherals enabled	
S32K116	25	Typ	26	40	1.05	1.07	TBD	6.3	7.2	11.8	20.3	NA						245
	85	Typ	76	93	1.1	1.11	TBD	6.6	7.5	12	20.6							251
		Max	287	300	1.39	1.4	NA	8	8.9	13.4	22.1							279
	105	Typ	139	164	1.15	1.16	TBD	6.8	7.7	12.3	20.8							255
		Max	590	603	1.68	1.69	NA	9.2	10.1	14.5	23.1							302
	125	Typ	NA	NA	NA	NA	TBD	NA	NA	NA	NA							NA
		Max	891	904	2.02	2.04	NA	10.4	11.3	15.6	24.1							325
S32K118	25	Typ	26	38	1.9	2.5	TBD	7	12	TBD	TBD	NA						TBD
	105	Typ	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD							TBD
		Max	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD							TBD
	125	Typ	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD							TBD
		Max	TBD	TBD	TBD	TBD	TBD	TBD	TBD	TBD	42							TBD
S32K142	25	Typ	29	40	1.17	1.21	2.19	6.4	7.4	17.3	24.6	24.5	31.3	28.8	37.5	40.5	52.2	360
	85	Typ	128	137	1.48	1.51	2.31	7	8	17.6	24.9	25	31.6	29.1	37.7	41.1	52.5	364
		Max	335	360	1.87	1.89	NA	8.6	9.4	22	28.2	26.9	33.5	32	40	44	55.6	400
	105	Typ	240	257	1.58	1.61	2.44	7.6	8.3	18.3	25.7	25.5	31.9	29.8	38	41.5	53.1	373
		Max	740	791	2.32	2.34	NA	9.9	10.9	23.1	30.2	27.8	35.3	33.8	40.7	44.9	57.4	423
	125	Typ	NA	NA	NA	NA	2.84	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA	NA

Table continues on the next page...

Table 16. Device clock specifications 1 (continued)

Symbol	Description	Min.	Max.	Unit
f _{FLASH}	Flash clock	—	24	MHz
Normal run mode (S32K14x series) ³				
f _{SYS}	System and core clock	—	80	MHz
f _{BUS}	Bus clock	—	40 ⁴	MHz
f _{FLASH}	Flash clock	—	26.67	MHz
VLPR mode ⁵				
f _{SYS}	System and core clock	—	4	MHz
f _{BUS}	Bus clock	—	4	MHz
f _{FLASH}	Flash clock	—	1	MHz
f _{ERCLK}	External reference clock	—	16	MHz

1. Refer to the section [Feature comparison](#) for the availability of modes and other specifications.
2. Only available on some devices. See section [Feature comparison](#).
3. With SPLP as system clock source.
4. 48 MHz when f_{SYS} is 48 MHz
5. The frequency limitations in VLPR mode here override any frequency specification listed in the timing specification for any other module.

6 Peripheral operating requirements and behaviors

6.1 System modules

There are no electrical specifications necessary for the device's system modules.

6.2 Clock interface modules

6.2.1 External System Oscillator electrical specifications

6.2.3 System Clock Generation (SCG) specifications

6.2.3.1 Fast internal RC Oscillator (FIRC) electrical specifications

Table 19. Fast internal RC Oscillator electrical specifications

Symbol	Parameter ¹	Value			Unit
		Min.	Typ.	Max.	
F_{FIRC}	FIRC target frequency	—	48	—	MHz
ΔF	Frequency deviation across process, voltage, and temperature < 105°C	—	±0.5	±1	% F_{FIRC}
ΔF_{125}	Frequency deviation across process, voltage, and temperature < 125°C	—	±0.5	±1.1	% F_{FIRC}
T_{Startup}	Startup time		3.4	5	μs ²
T_{JIT}^3	Cycle-to-Cycle jitter	—	300	500	ps
T_{JIT}^3	Long term jitter over 1000 cycles	—	0.04	0.1	% F_{FIRC}

1. With FIRC regulator enable

2. Startup time is defined as the time between clock enablement and clock availability for system use.

3. FIRC as system clock

NOTE

Fast internal RC Oscillator is compliant with CAN and LIN standards.

6.2.3.2 Slow internal RC oscillator (SIRC) electrical specifications

Table 20. Slow internal RC oscillator (SIRC) electrical specifications

Symbol	Parameter	Value			Unit
		Min.	Typ.	Max.	
F_{SIRC}	SIRC target frequency	—	8	—	MHz
ΔF	Frequency deviation across process, voltage, and temperature < 105°C	—	—	±3	% F_{SIRC}
ΔF_{125}	Frequency deviation across process, voltage, and temperature < 125°C	—	—	±3.3	% F_{SIRC}
T_{Startup}	Startup time	—	9	12.5	μs ¹

1. Startup time is defined as the time between clock enablement and clock availability for system use.

6.3.1.1 Flash timing specifications — commands

Table 23. Flash command timing specifications for S32K14x

Symbol	Description ¹		S32K142		S32K144		S32K146		S32K148		Unit Notes	
			Typ	Max	Typ	Max	Typ	Max	Typ	Max		
t_{rd1blk}	Read 1 Block execution time	32 KB flash	—	—	—	—	—	—	—	—	ms	
		64 KB flash	—	0.5	—	0.5	—	0.5	—	—		
		128 KB flash	—	—	—	—	—	—	—	—		
		256 KB flash	—	2	—	—	—	—	—	—		
		512 KB flash	—	—	—	1.8	—	2	—	2		
t_{rd1sec}	Read 1 Section execution time	2 KB flash	—	75	—	75	—	75	—	75	μ s	
		4 KB flash	—	100	—	100	—	100	—	100		
t_{pgmchk}	Program Check execution time	—	—	95	—	95	—	95	—	100	μ s	
t_{pgm8}	Program Phrase execution time	—	90	225	90	225	90	225	90	225	μ s	
t_{ersblk}	Erase Flash Block execution time	32 KB flash	—	—	—	—	—	—	—	—	ms	2
		64 KB flash	30	550	30	550	30	550	—	—		
		128 KB flash	—	—	—	—	—	—	—	—		
		256 KB flash	250	2125	—	—	—	—	—	—		
		512 KB flash	—	—	250	4250	250	4250	250	4250		
t_{ersscr}	Erase Flash Sector execution time	—	12	130	12	130	12	130	12	130	ms	2
$t_{pgmsec1k}$	Program Section execution time (1KB flash)	—	5	—	5	—	5	—	5	—	ms	
t_{rd1all}	Read 1s All Block execution time	—	—	2.8	—	2.3	—	5.2	—	8.2	ms	
t_{rdonce}	Read Once execution time	—	—	30	—	30	—	30	—	30	μ s	
$t_{pgmonce}$	Program Once execution time	—	90	—	90	—	90	—	90	—	μ s	
t_{ersall}	Erase All Blocks execution time	—	250	2800	400	4900	700	10000	1400	17000	ms	2
t_{vfykey}	Verify Backdoor Access Key execution time	—	—	35	—	35	—	35	—	35	μ s	
$t_{ersallu}$	Erase All Blocks Unsecure execution time	—	250	2800	400	4900	700	10000	1400	17000	ms	2
$t_{pgmpart}$	Program Partition for EEPROM backup execution time	32 KB EEPROM backup	70	—	70	—	70	—	—	—	ms	3
		64 KB EEPROM backup	71	—	71	—	71	—	150	—		

Table continues on the next page...

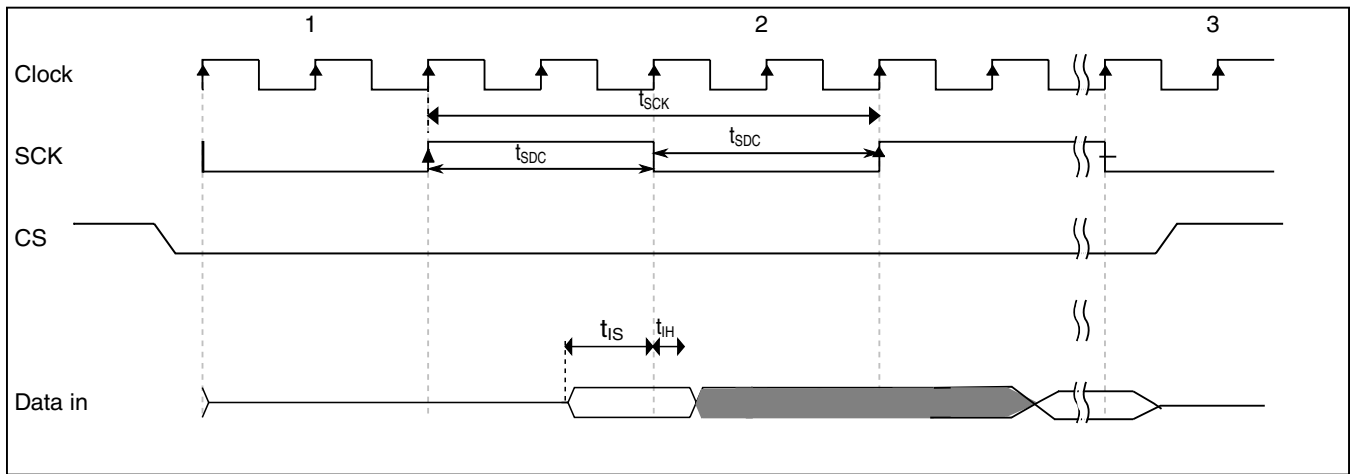


Figure 9. QuadSPI input timing (SDR mode) diagram

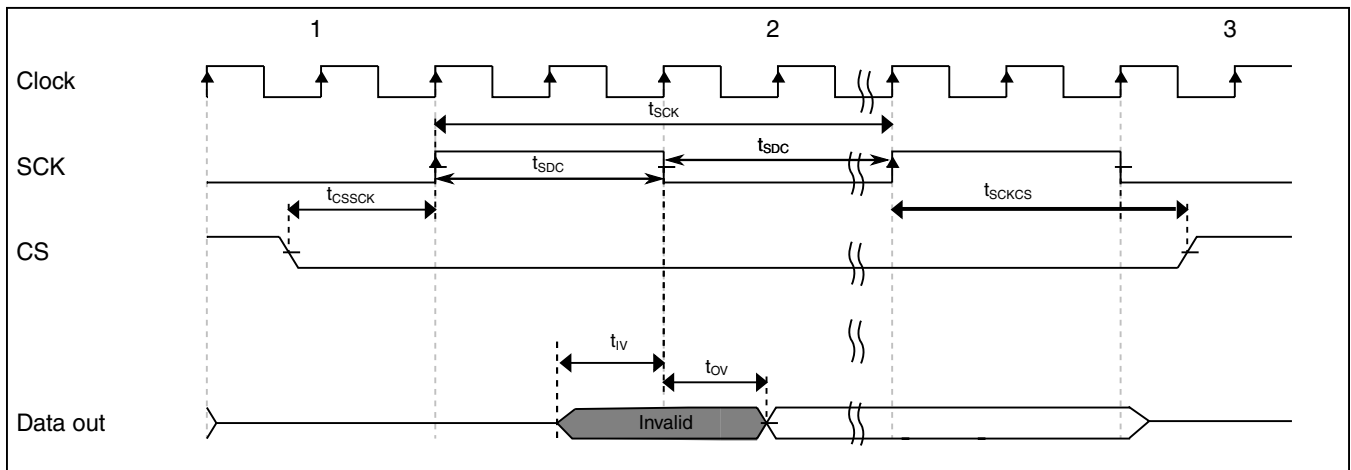
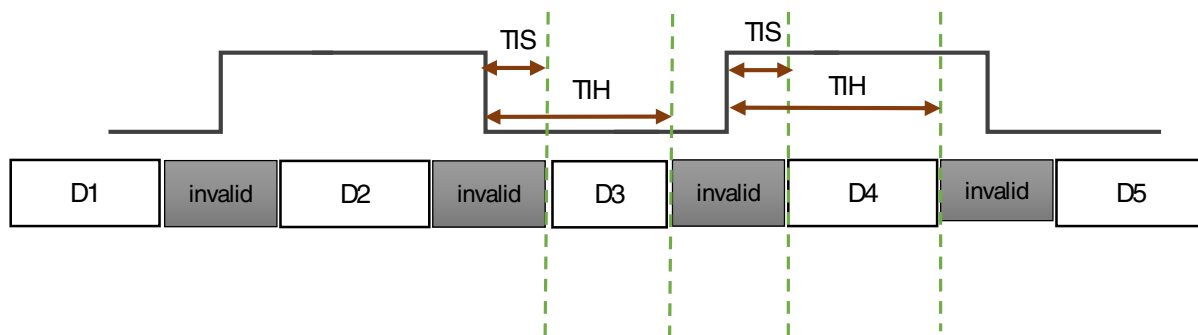


Figure 10. QuadSPI output timing (SDR mode) diagram



TIS – Setup Time

TIH – Hold Time

Figure 11. QuadSPI input timing (HyperRAM mode) diagram

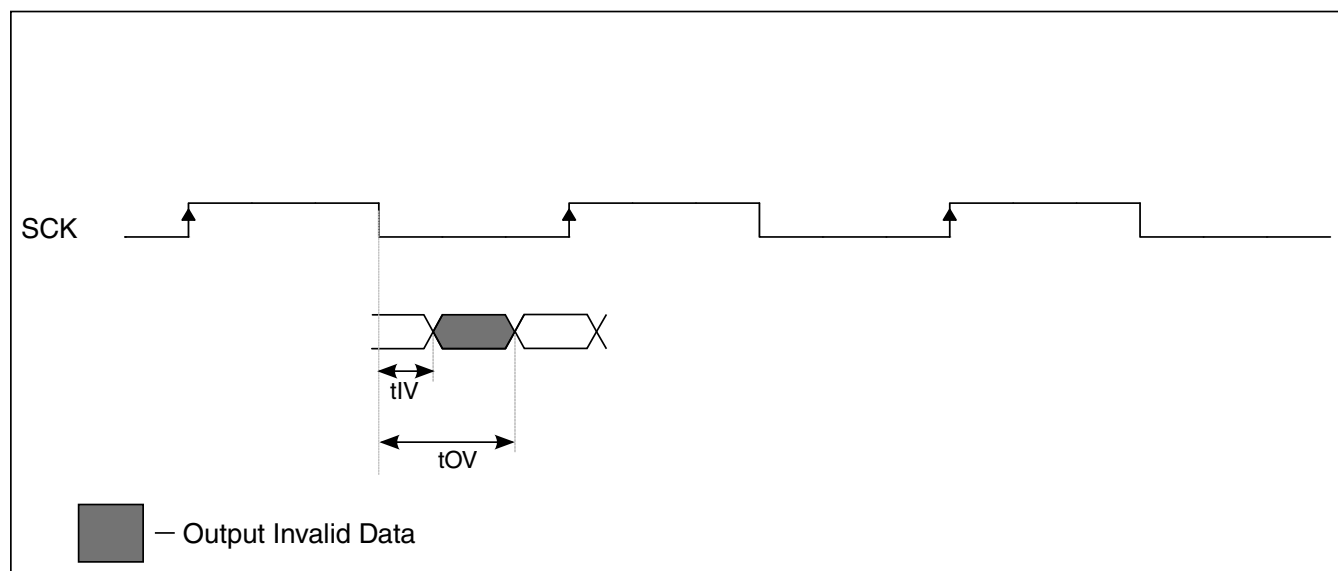


Figure 12. QuadSPI output timing (HyperRAM mode) diagram

6.4 Analog modules

6.4.1 ADC electrical specifications

6.4.1.1 12-bit ADC operating conditions

Table 27. 12-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
V_{REFH}	ADC reference voltage high		See Voltage and current operating requirements for values	V_{DDA}	See Voltage and current operating requirements for values	V	2
V_{REFL}	ADC reference voltage low		See Voltage and current operating requirements for values	0	See Voltage and current operating requirements for values	mV	2
V_{ADIN}	Input voltage		V_{REFL}	—	V_{REFH}	V	
R_S	Source impedandance	$f_{ADCK} < 4 \text{ MHz}$	—	—	5	k Ω	
R_{SW1}	Channel Selection Switch Impedance		—	0.75	1.2	k Ω	
R_{AD}	Sampling Switch Impedance		—	2	5	k Ω	
C_{P1}	Pin Capacitance		—	10	—	pF	
C_{P2}	Analog Bus Capacitance		—	—	4	pF	
C_S	Sampling capacitance		—	4	5	pF	

Table continues on the next page...

6.4.1.2 12-bit ADC electrical characteristics

NOTE

- ADC performance specifications are documented using a single ADC. For parallel/simultaneous operation of both ADCs, either for sampling the same channel by both ADCs or for sampling different channels by each ADC, some amount of decrease in performance can be expected. Care must be taken to stagger the two ADC conversions, in particular the sample phase, to minimize the impact of simultaneous conversions.
- On reduced pin packages where ADC reference pins are shared with supply pins, ADC analog performance characteristics may be impacted. The amount of variation will be directly impacted by the external PCB layout and hence care must be taken with PCB routing. See [AN5426](#) for details

Table 28. 12-bit ADC characteristics (2.7 V to 3 V) ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SS}$)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
V_{DDA}	Supply voltage		2.7	—	3	V	
I_{DDA_ADC}	Supply current per ADC		—	0.6	—	mA	3
SMPLTS	Sample Time		275	—	Refer to the <i>Reference Manual</i>	ns	
TUE ⁴	Total unadjusted error		—	±4	±8	LSB ⁵	6, 7, 8, 9
DNL	Differential non-linearity		—	±1.0	—	LSB ⁵	6, 7, 8, 9
INL	Integral non-linearity		—	±2.0	—	LSB ⁵	6, 7, 8, 9

1. All accuracy numbers assume the ADC is calibrated with $V_{REFH}=V_{DDA}=V_{DD}$, with the calibration frequency set to less than or equal to half of the maximum specified ADC clock frequency.
2. Typical values assume $V_{DDA} = 3\text{ V}$, $\text{Temp} = 25\text{ }^{\circ}\text{C}$, $f_{ADCK} = 40\text{ MHz}$, $R_{AS}=20\text{ }\Omega$, and $C_{AS}=10\text{ nF}$.
3. The ADC supply current depends on the ADC conversion rate.
4. Represents total static error, which includes offset and full scale error.
5. $1\text{ LSB} = (V_{REFH} - V_{REFL})/2^N$
6. The specifications are with averaging and in standalone mode only. Performance may degrade depending upon device use case scenario. When using ADC averaging, refer to the *Reference Manual* to determine the most appropriate settings for AVGS.
7. For ADC signals adjacent to V_{DD}/V_{SS} or XTAL/EXTAL or high frequency switching pins, some degradation in the ADC performance may be observed.
8. All values guarantee the performance of the ADC for multiple ADC input channel pins. When using ADC to monitor the internal analog parameters, assume minor degradation.
9. All the parameters in the table are given assuming system clock as the clocking source for ADC.

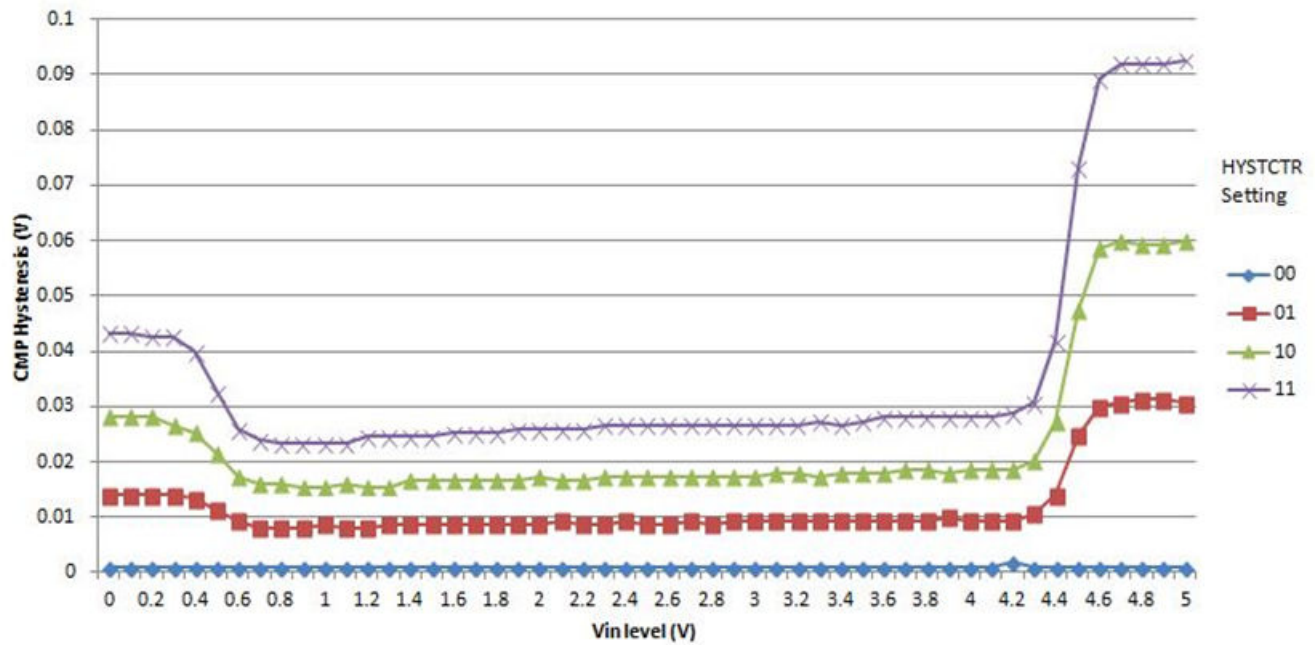


Figure 16. Typical hysteresis vs. Vin level (VDDA = 5 V, PMODE = 0)

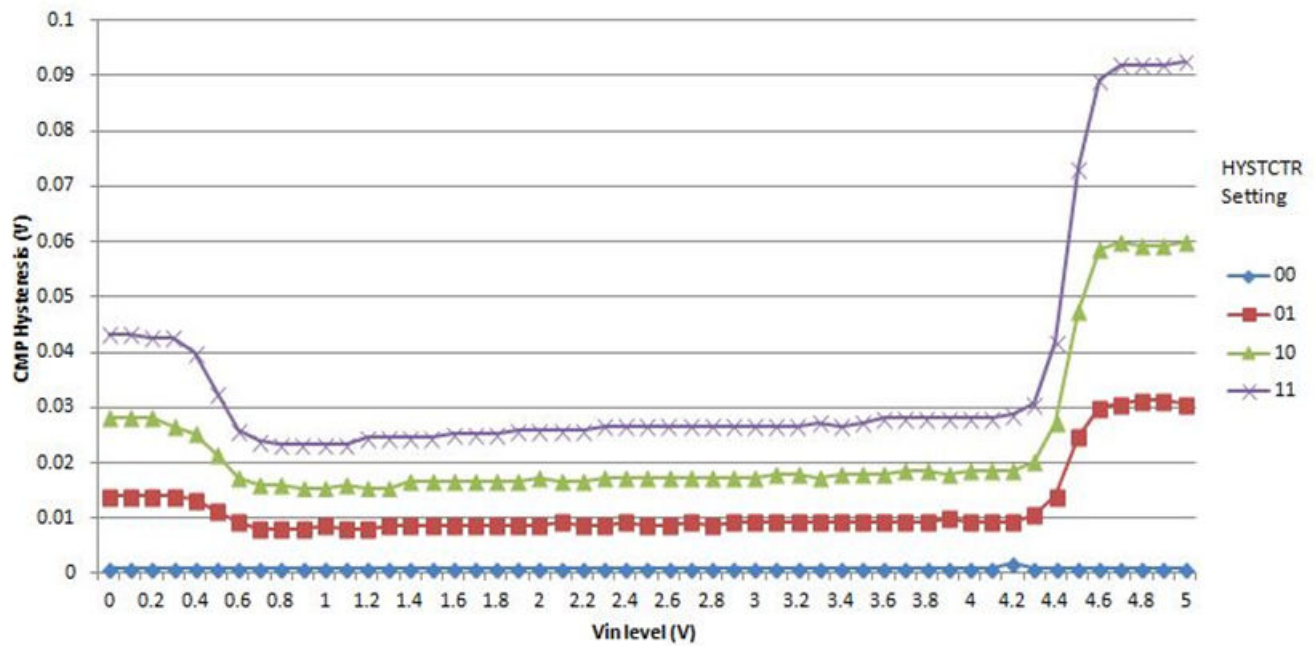


Figure 17. Typical hysteresis vs. Vin level (VDDA = 5 V, PMODE = 1)

Table 32. LPSPI electrical specifications¹

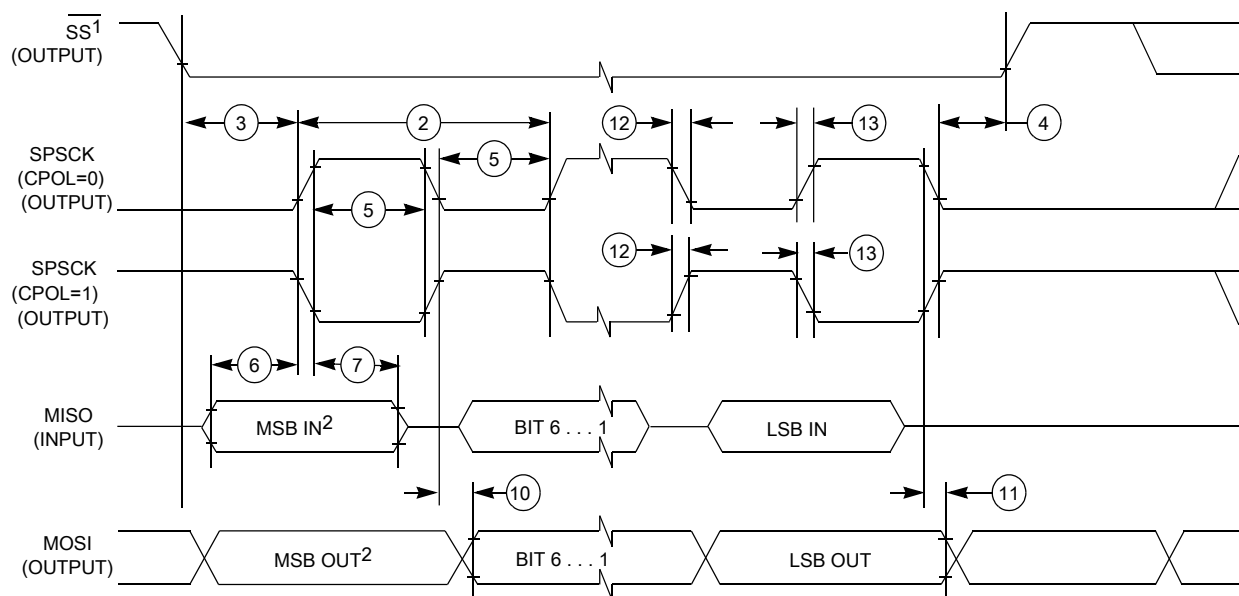
Num	Symbol	Description	Conditions	Run Mode ²				HSRUN Mode ²				VLPR Mode				Unit
				5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
				Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
	f _{periph} ^{3, 4}	Peripheral Frequency	Slave	-	40	-	40	-	56	-	56	-	4	-	4	MHz
			Master	-	40	-	40	-	56	-	56	-	4	-	4	
			Master Loopback ⁵	-	40	-	48	-	48	-	48	-	4	-	4	
			Master Loopback(slow) ⁶	-	48	-	48	-	48	-	48	-	4	-	4	
1	f _{op}	Frequency of operation	Slave	-	10	-	10	-	14	-	14 ⁷	-	2	-	2	MHz
			Master	-	10	-	10	-	14	-	14 ⁷	-	2	-	2	
			Master Loopback ⁵	-	20	-	12	-	24	-	12	-	2	-	2	
			Master Loopback(slow) ⁶	-	12	-	12	-	12	-	12	-	2	-	2	
2	t _{SPSCK}	SPSCK period	Slave	100	-	100	-	72	-	72	-	500	-	500	-	ns
			Master	100	-	100	-	72	-	72	-	500	-	500	-	
			Master Loopback ⁵	50	-	83	-	42	-	83	-	500	-	500	-	
			Master Loopback(slow) ⁶	83	-	83	-	83	-	83	-	500	-	500	-	
3	t _{Lead} ⁸	Enable lead time (PCS to SPSCK delay)	Slave	-	-	-	-	-	-	-	-	-	-	-	-	ns
			Master	(PCSSCK+1)*t _{periph} -25	-	(PCSSCK+1)*t _{periph} -25	-	(PCSSCK+1)*t _{periph} -25	-	(PCSSCK+1)*t _{periph} -25	(PCSSCK+1)*t _{periph} -50	-	(PCSSCK+1)*t _{periph} -50	-		
			Master Loopback ⁵													
			Master Loopback(slow) ⁶													

Table continues on the next page...

Table 32. LPSPI electrical specifications¹ (continued)

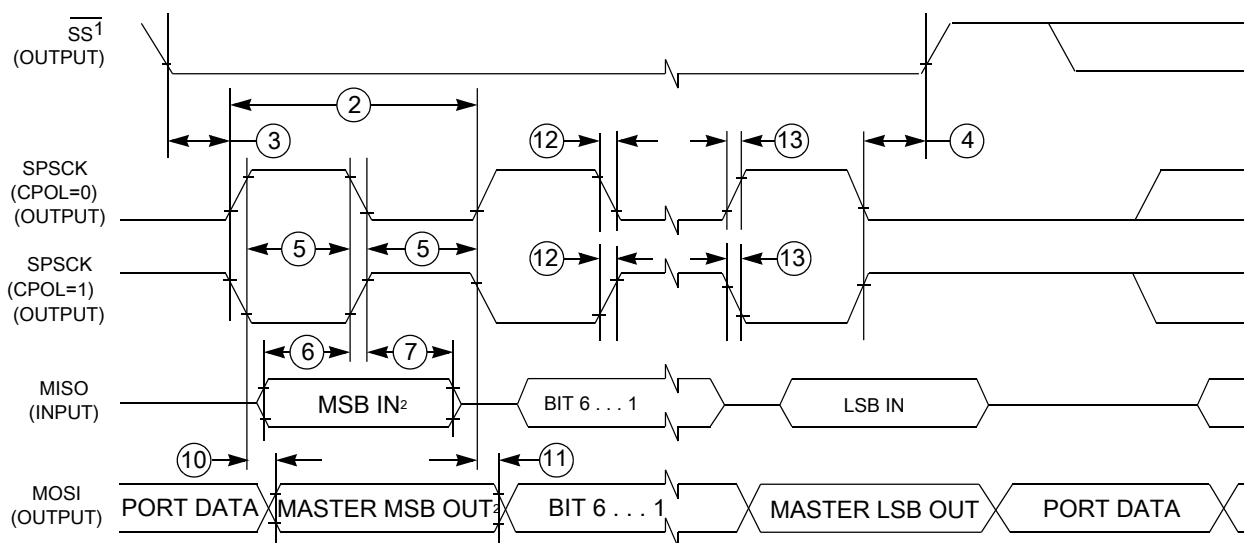
Num	Symbol	Description	Conditions	Run Mode ²				HSRUN Mode ²				VLPR Mode				Unit
				5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
				Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
8	t _a	Slave access time	Slave	-	50	-	50	-	50	-	50	-	100	-	100	ns
9	t _{dis}	Slave MISO (SOUT) disable time	Slave	-	50	-	50	-	50	-	50	-	100	-	100	ns
10	t _v	Data valid (after SPSCCK edge)	Slave	-	30	-	39	-	26	-	36 ¹¹ 31 ¹²	-	92	-	96	ns
			Master	-	12	-	16	-	11	-	15	-	47	-	48	
			Master Loopback ⁵	-	12	-	16	-	11	-	15	-	47	-	48	
			Master Loopback(slow) ⁶	-	8	-	10	-	7	-	9	-	44	-	44	
11	t _{HO}	Data hold time(outputs)	Slave	4	-	4	-	4	-	4	-	4	-	4	-	ns
			Master	-15	-	-22	-	-15	-	-23	-	-22	-	-29	-	
			Master Loopback ⁵	-10	-	-14	-	-10	-	-14	-	-14	-	-19	-	
			Master Loopback(slow) ⁶	-15	-	-22	-	-15	-	-22	-	-21	-	-27	-	
12	t _{RI/FI}	Rise/Fall time input	Slave	-	1	-	1	-	1	-	1	-	1	-	1	ns
			Master	-		-		-		-		-		-		
			Master Loopback ⁵	-		-		-		-		-		-		
			Master Loopback(slow) ⁶	-		-		-		-		-		-		
13	t _{RO/FO}	Rise/Fall time output	Slave	-	25	-	25	-	25	-	25	-	25	-	25	ns
			Master	-		-		-		-		-		-		
			Master Loopback ⁵	-		-		-		-		-		-		

Table continues on the next page...



1. If configured as an output.
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 18. LPSPI master mode timing (CPHA = 0)

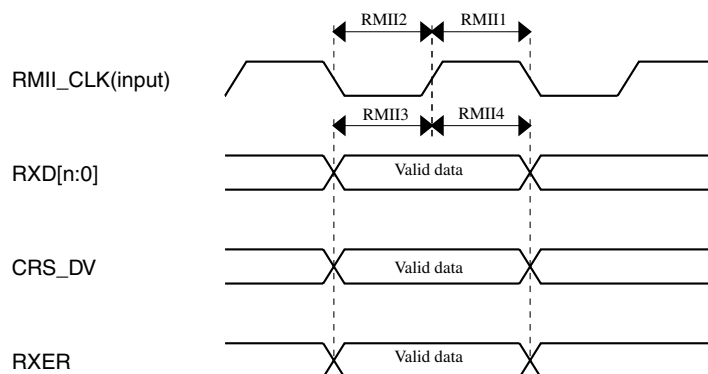
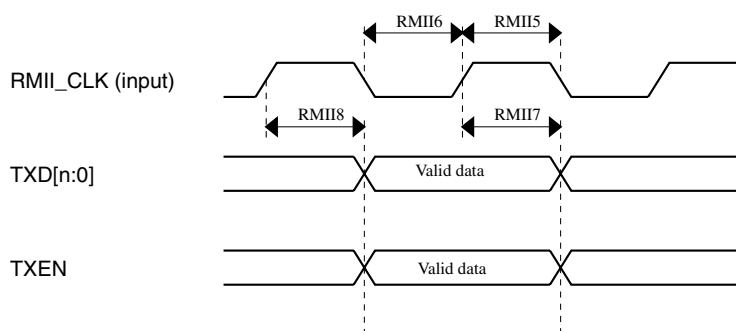


1. If configured as output
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 19. LPSPI master mode timing (CPHA = 1)

**Table 36. RMI signal switching specifications
(continued)**

Symbol	Description	Min.	Max.	Unit
RMII7	RMII_CLK to TXD[1:0], TXEN invalid	2	—	ns
RMII8	RMII_CLK to TXD[1:0], TXEN valid	—	15	ns

**Figure 26. RMI receive diagram****Figure 27. RMI transmit diagram**

The following table describes the MDIO electrical characteristics.

- Measurements are with maximum output load of 25 pF, input transition of 1 ns and pad configured with fastest slew settings (DSE = 1'b1).
- I/O operating voltage ranges from 2.97 V to 3.6 V
- While doing the mode transition (RUN -> HSRUN or HSRUN -> RUN), the interface should be OFF.
- MDIO pin must have external Pull-up.

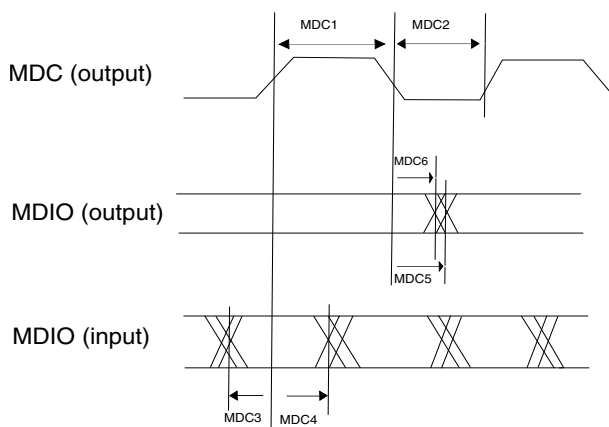
Table 37. MDIO timing specifications

Symbol	Description	Min.	Max.	Unit
—	MDC Clock Frequency	—	2.5	MHz

Table continues on the next page...

Table 37. MDIO timing specifications (continued)

Symbol	Description	Min.	Max.	Unit
MDC1	MDC pulse width high	40%	60%	MDC period
MDC2	MDC pulse width low	40%	60%	MDC period
MDC3	MDIO (input) to MDC rising edge setup	25	—	ns
MDC4	MDIO (input) to MDC rising edge hold	0	—	ns
MDC5	MDC falling edge to MDIO output valid (maximum propagation delay)	—	25	ns
MDC6	MDC falling edge to MDIO output invalid (minimum propagation delay)	-10	—	ns

**Figure 28. MII/RMII serial management channel timing diagram**

6.5.7 Clockout frequency

Maximum supported clock out frequency for this device is 20 MHz

6.6 Debug modules

6.6.1 SWD electrical specifications

Table 38. SWD electrical specifications

Symbol	Description	Run Mode				HSRUN Mode				VLPR Mode				Unit
		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		5.0 V IO		3.3 V IO		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
S1	SWD_CLK frequency of operation	-	25	-	25	-	25	-	25	-	10	-	10	MHz
S2	SWD_CLK cycle period	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	1/S1	-	ns
S3	SWD_CLK clock pulse width	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	S2/2 - 5	S2/2 + 5	ns
S4	SWD_CLK rise and fall times	-	1	-	1	-	1	-	1	-	1	-	1	ns
S9	SWD_DIO input data setup time to SWD_CLK rise	4	-	4	-	4	-	4	-	16	-	16	-	ns
S10	SWD_DIO input data hold time after SWD_CLK rise	3	-	3	-	3	-	3	-	10	-	10	-	ns
S11	SWD_CLK high to SWD_DIO data valid	-	28	-	38	-	28	-	38	-	70	-	77	ns
S12	SWD_CLK high to SWD_DIO high-Z	-	28	-	38	-	28	-	38	-	70	-	77	ns
S13	SWD_CLK high to SWD_DIO data invalid	0	-	0	-	0	-	0	-	0	-	0	-	ns

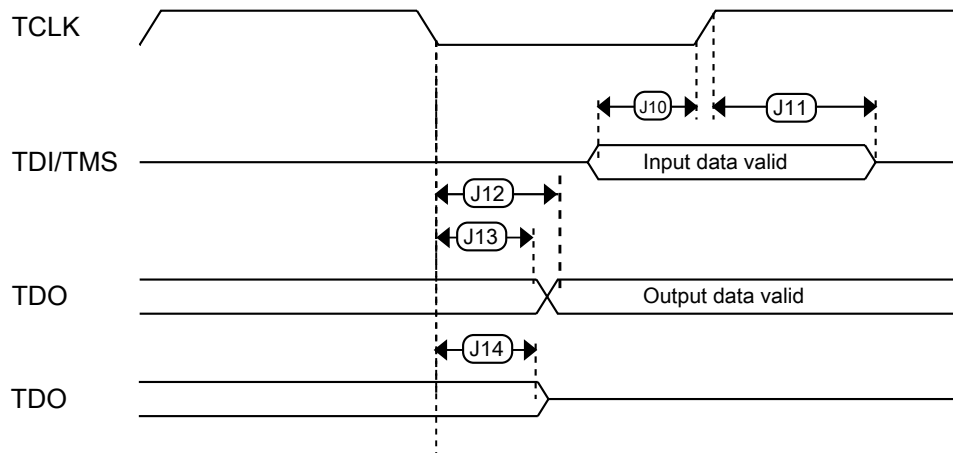


Figure 34. Test Access Port timing

7 Thermal attributes

7.1 Description

The tables in the following sections describe the thermal characteristics of the device.

NOTE

Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting side (board) temperature, ambient temperature, air flow, power dissipation or other components on the board, and board thermal resistance.

7.2 Thermal characteristics

Table 41. Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package (continued)

Rating	Conditions	Symbol	Package	Values						Unit	
				S32K116	S32K118	S32K142	S32K144	S32K146	S32K148		
			144	NA	NA	NA	NA	37	31		
			176	NA	NA	NA	NA	NA	30		
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1, 3}	Four layer board (2s2p)	R _{θJMA}	32	26	NA	NA	NA	NA	NA		
			48	48	41	NA	NA	NA	NA		
			64	NA	37	36	36	35	NA		
			100	NA	NA	34	34	33	NA		
			144	NA	NA	NA	NA	36	30		
			176	NA	NA	NA	NA	NA	29		
			Thermal resistance, Junction to Board ⁴	—	R _{θJB}	32	11	NA	NA		NA
48	33	24				NA	NA	NA	NA		
64	NA	26				25	25	23	NA		
100	NA	NA				25	25	24	NA		
144	NA	NA				NA	NA	30	24		
176	NA	NA				NA	NA	NA	24		
Thermal resistance, Junction to Case ⁵	—	R _{θJC}	32	NA	NA	NA	NA	NA	NA		
			48	23	19	NA	NA	NA	NA		
			64	NA	14	13	12	11	NA		
			100	NA	NA	13	12	11	NA		
			144	NA	NA	NA	NA	12	9		
			176	NA	NA	NA	NA	NA	9		
Thermal resistance, Junction to Case (Bottom) ⁶	—	R _{θJCBottom}	32	1	NA						
			48	NA							
			64								
			100								
			144								
			176								

Table continues on the next page...

Table 42. Thermal characteristics for the 100 MAPBGA package

Rating	Conditions	Symbol	Values			Unit
			S32K146	S32K144	S32K148	
Thermal resistance, Junction to Ambient (Natural Convection) ^{1, 2}	Single layer board (1s)	R _{θJA}	57.2	61.0	52.5	°C/W
Thermal resistance, Junction to Ambient (Natural Convection) ^{1, 2, 3}	Four layer board (2s2p)	R _{θJA}	32.1	35.6	27.5	°C/W
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1, 2, 3}	Single layer board (1s)	R _{θJMA}	44.1	46.6	39.0	°C/W
Thermal resistance, Junction to Ambient (@200 ft/min) ^{1, 3}	Two layer board (2s2p)	R _{θJMA}	27.2	30.9	22.8	°C/W
Thermal resistance, Junction to Board ⁴	—	R _{θJB}	15.3	18.9	11.2	°C/W
Thermal resistance, Junction to Case ⁵	—	R _{θJC}	10.2	14.2	7.5	°C/W
Thermal resistance, Junction to Package Top outside center ⁶	—	Ψ _{JT}	0.2	0.4	0.2	°C/W
Thermal resistance, Junction to Package Bottom outside center ⁷	—	Ψ _{JB}	12.2	15.9	18.3	°C/W

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per SEMI G38-87 and JEDEC JESD51-2 with the single layer board horizontal.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.
7. Thermal characterization parameter indicating the temperature difference between package bottom center and the junction temperature per JEDEC JESD51-12. When Greek letters are not available, the thermal characterization parameter is written as Psi-JB.

Table 43. Revision History

Rev. No.	Date	Substantial Changes
		- Added footnotes V_{ih} Input Buffer High Voltage and V_{ih} Input Buffer Low Voltage - Updated table: AC electrical specifications at 3.3 V range - Updated table: AC electrical specifications at 5 V range - In table: Standard input pin capacitance - Added footnote to Normal run mode (S32K14x series) - Removed note from 1M ohms Feedback Resistor in figure Oscillator connections scheme - In table: External System Oscillator electrical specifications - Updated typical of I_{DDOSC} Supply current — low-gain mode (low-power mode) (HGO=0) 1 for 4 and 8 MHz - Removed rows for I_{lk_ext} EXTAL/XTAL impedance High-frequency, low-gain mode (low-power mode) and high-frequency, high-gain mode and V_{EXTAL} - Updated Typ. of R_S low-gain mode - Updated description of R_F, R_S, and V_{PP} - Removed footnote from R_F Feedback resistor - Updated footnote for C_1 C_2 and R_F - In table: Table 18 - Removed mention of high-frequency - Added HGO 0, 1 information - In table: Fast internal RC Oscillator electrical specifications - Updated F_{FIRC} - Updated description of ΔF - Updated typ and max values of T_{JIT} cycle-to-cycle jitter and T_{JIT} Long term jitter over 1000 cycles - Added footnotes to T_{JIT} cycle-to-cycle jitter and T_{JIT} Long term jitter over 1000 cycles - Updated naming convention of I_{DDFIRC} Supply current - Added footnote to I_{DDFIRC} Supply current - Added footnote to column Parameter - In table: Slow internal RC oscillator (SIRC) electrical specifications - Removed V_{DD} Supply current in 2 MHz Mode - Removed footnote and updated description of ΔF - Updated footnote to F_{SIRC} and I_{DDSIRC} - In table: SPLL electrical specifications - Added row for F_{SPLL_REF} PLL Reference - Updated naming convention throughout the table - Updated the max value of T_{SPLL_LOCK} Lock detector detection time - In table: Flash timing specifications — commands - Added footnotes: - All command times assumes ... - For all EEPROM Emulation terms ... 'First time' EERAM writes after a POR ... - Removed footnote 'Assumes 25 MHz or ...' - Updated Max of $t_{ewr32bers}$ - Added parameters $t_{quickwr}$ and $t_{quickwrCinup}$ - In table: Reliability specifications - Removed Typ. values for all parameters - Removed footnote 'Typical values represent ...' - Added footnote 'Any other EEE driver usage ...' - Updated QuadSPI AC specifications - Removed topic: Reliability, Safety and Security modules - In table: 12-bit ADC operating conditions - Updated V_{DDA}

Table continues on the next page...

Table 43. Revision History (continued)

Rev. No.	Date	Substantial Changes
		- Fixed the typo in R_{SW1} - In LPSPi electrical specifications : - Updated t_{Lead} and t_{Lag} - Added footnote in Figure: LPSPi slave mode timing (CPHA = 0) and Figure: LPSPi slave mode timing (CPHA = 1) - In Thermal characteristics : - Updated the name of table: Thermal characteristics for 32-pin QFN and 48/64/100/144/176-pin LQFP package - Deleted specs for $R_{\theta JC}$ for 32 QFN package - Added '$R_{\theta JCBottom}$'
8	18 June 2018	- In attachment 'S32K1xx_Power_Modes_Configuration': - Updated VLPR peripherals disabled and Peripherals Enabled use case #1, using 4 Mhz for System clock, 2 Mhz for bus clock, and 1Mhz for flash. - Removed S32K116 from Notes - In figure: S32K1xx product series comparison : - Added note 'Availability of peripherals depends on the pin availability ...' - Updated 'Ambient Operation Temperature' row - Updated 'System RAM (including FlexRAM and MTB)' row for S32K144, S32K146, and S32K148 - In Ordering information : - Updated figure for 'Y: Optional feature' - Updated footnote 3 - In Power and ground pins : - In figure 'Power diagram', updated V_{Flash} frequency to 3.3 V - In Power mode transition operating behaviors : - Updated footnote for 'VLPS Mode: All clock sources disabled' - In Power consumption : - Added IDD's for S32K116 - Added VLPR Peripherals enabled use case 2 at 125 °C/Typicals - Renamed VLPR 'Peripherals enabled' to 'Peripherals enabled use case 1' - Added footnote 'Data collected using RAM' to VLPR 'Peripherals disabled' and VLPR 'Peripherals enabled use case 1' - Updated VLPS Peripherals enabled at 25 °C/Typicals for S32K142 and S32K144 to 40 μA and 42 μA respectively - Added table 'VLPS additional use-case power consumption at typical conditions' - In DC electrical specifications at 3.3 V Range : - Updated naming conventions - Added specs for GPIO-FAST pad - In DC electrical specifications at 5.0 V Range : - Updated naming conventions - Added specs for GPIO-FAST pad - In AC electrical specifications at 3.3 V range : - Updated naming conventions - Added specs for GPIO-FAST pad - In AC electrical specifications at 5 V range : - Updated naming conventions - Added specs for GPIO-FAST pad - In External System Oscillator electrical specifications : - Clarified description of g_{mXOSC} - Updated V_{IL} max. to 1.15 V - In Fast internal RC Oscillator (FIRC) electrical specifications :